

INTERNATIONAL STANDARD



**Electromagnetic compatibility (EMC) –
Part 4-3: Testing and measurement techniques – Radiated, radio-frequency
electromagnetic field immunity test**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

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CONTENTS

FOREWORD	6
INTRODUCTION	8
1 Scope	9
2 Normative references	9
3 Terms, definitions and abbreviated terms	9
3.1 Terms and definitions	9
3.2 Abbreviated terms	13
4 General	14
5 Test levels and frequency ranges	14
5.1 Selection of test level	14
5.2 Test frequency ranges	16
6 Test equipment	17
6.1 Test instrumentation	17
6.2 Description of the test facility	17
6.3 Uniform field area (UFA)	18
6.3.1 Characteristics of the UFA	18
6.3.2 Constant field strength level setting method	23
6.3.3 Constant power level setting method	24
7 Test setup	25
7.1 General	25
7.2 Arrangement of table-top equipment	26
7.3 Arrangement of floor-standing equipment	28
7.4 Arrangement of wiring	29
7.5 Arrangement of human body-mounted equipment	30
8 Test procedure	30
8.1 General	30
8.2 Laboratory reference conditions	30
8.2.1 General	30
8.2.2 Climatic conditions	30
8.2.3 Electromagnetic conditions	30
8.3 Execution of the test	30
8.4 Step sizes	32
9 Evaluation of test results	32
10 Test report	32
Annex A (informative) Rationale for the choice of modulation for tests related to the protection against RF emissions from digital radio services	34
A.1 Summary of available modulation methods	34
A.2 Experimental results	35
A.3 Secondary modulation effects	38
A.4 Conclusion	38
Annex B (informative) Field generating antennas	39
B.1 Biconical antenna	39
B.2 Log-periodic antenna	39
B.3 Combination antennas	39
B.4 Horn antenna and double ridge wave guide antenna	39

Annex C (informative) Use of anechoic chambers	40
C.1 General anechoic chamber information	40
C.2 Use of ferrite-lined chambers at frequencies above 1 GHz	40
C.2.1 Problems caused by the use of ferrite-lined chambers for radiated field immunity tests at frequencies above 1 GHz	40
C.2.2 Solutions to reduce reflections	41
Annex D (informative) Amplifier compression and non-linearity	42
D.1 Objective of limiting amplifier distortion	42
D.2 Possible problems caused by harmonics and saturation	42
D.3 Limiting the harmonic content in the field	42
D.4 Effect of linearity characteristic on the immunity test	43
D.4.1 General	43
D.4.2 Evaluation method of the linearity characteristic	43
Annex E (informative) Guidance for product committees on the selection of test levels	47
E.1 General	47
E.2 Test levels related to general purposes	47
E.3 Test levels related to the protection against RF emissions from digital radio telephones	48
E.4 Special measures for fixed transmitters	49
Annex F (informative) Selection of test methods	50
Annex G (informative) Cable layout details	52
G.1 Intentions of EUT setup for radiated immunity test	52
G.2 Cable in the field	52
G.3 Cables leaving the test area	52
G.4 Turning the EUT cabinets	52
Annex H (informative) Examples of test setups for large and heavy EUTs	54
H.1 EUTs with bottom fed cables	54
H.2 EUTs with overhead cables	55
H.3 EUTs with multiple cables and AEs	56
H.4 Large EUTs with side fed cables and multiple UFA windows	57
Annex I (informative) Testing with multiple signals	58
I.1 General	58
I.2 Intermodulation	58
I.3 Power requirements	59
I.4 Level setting requirements	60
I.5 Linearity and harmonics checks	60
I.6 EUT performance criteria with multiple signals	60
Annex J (informative) Measurement uncertainty due to test instrumentation	61
J.1 General	61
J.2 Uncertainty budgets for level setting	61
J.2.1 Definition of the measurand	61
J.2.2 MU contributors of the measurand	61
J.2.3 Calculation examples for expanded uncertainty	62
J.2.4 Explanation of terms	63
J.3 Application	64
J.4 Reference documents	64
Annex K (informative) Calibration method for E-field probes	65
K.1 Overview	65

K.2	Probe calibration requirements	65
K.2.1	General	65
K.2.2	Calibration frequency range	65
K.2.3	Frequency steps	65
K.2.4	Field strength	66
K.3	Requirements for calibration instrumentation	66
K.3.1	General	66
K.3.2	Harmonics and spurious signals	66
K.3.3	Linearity check for probe	67
K.3.4	Determination of the gain of the standard horn antennas	68
K.4	Field probe calibration in anechoic chambers	69
K.4.1	Calibration environments	69
K.4.2	Validation of anechoic chambers for field probe calibration	69
K.4.3	Probe calibration procedure	75
K.5	Other probe calibration environments and methods	77
K.5.1	General	77
K.5.2	Field probe calibration using TEM cells	77
K.5.3	Field probe calibration using waveguide chambers	78
K.5.4	Field probe calibration using open-ended waveguides	79
K.5.5	Calibration of field probes by gain transfer method	79
K.6	Reference documents	79
Bibliography		81

Figure 1 – Definition of the 80 % amplitude modulated (AM) test signal and the waveshapes occurring	16
Figure 2 – Example of suitable test facility	18
Figure 3 – Level setting setup	19
Figure 4 – Dimensions of sixteen-point uniform field area	20
Figure 5 – Minimum UFA size having a fifth grid point in the centre	21
Figure 6 – Measuring setup	23
Figure 7 – Example of EUT setup and cable layout for table top EUT having a cable that leaves the test setup	26
Figure 8 – Example of EUT setup (top view)	28
Figure C.1 – Multiple reflections in an existing small anechoic chamber	41
Figure C.2 – Most of the reflected waves are eliminated (applies for top and side view)	41
Figure D.1 – Amplifier linearity measurement setup	44
Figure D.2 – Example of linearity curve	45
Figure D.3 – Example of gain deviation	45
Figure H.1 – Example of a test setup for EUT with bottom fed underground cables (CMADs not shown)	54
Figure H.2 – Example of a test setup for EUTs with overhead cables	55
Figure H.3 – Example of a setup of EUTs with multiple cables and AEs	56
Figure H.4 – Large EUTs with side fed cables and multiple UFAs	57
Figure I.1 – Test frequencies f_1 and f_2 and intermodulation frequencies of the second and third order	58
Figure J.1 – Example of influences upon level setting	62
Figure K.1 – Example of linearity for probe	68

Figure K.2 – Setup for measuring net power to a transmitting device	70
Figure K.3 – Test setup for chamber validation test.....	72
Figure K.4 – Detail for measurement position ΔL	72
Figure K.5 – Example of data adjustment.....	73
Figure K.6 – Example of the test layout for antenna and probe	74
Figure K.7 – Test setup for chamber validation test.....	74
Figure K.8 – Example of alternative chamber validation data	75
Figure K.9 – Field probe calibration layout.....	76
Figure K.10 – Field probe calibration layout (top view).....	76
Figure K.11 – Cross-sectional view of a waveguide chamber	78
 Table 1 – Test levels.....	 15
Table 2 – Amplitude modulation characteristics at output of signal generator.....	15
Table 3 – Requirements for uniform field area for application of full illumination and partial illumination.....	22
Table A.1 – Comparison of modulation methods	35
Table A.2 – Relative interference levels	36
Table A.3 – Relative immunity levels.....	37
Table E.1 – Examples of test levels, associated protection distances and performance criteria	48
Table J.1 – Level setting process.....	62
Table J.2 – Test process.....	63
Table K.1 – Calibration field strength level.....	66
Table K.2 – Example for the probe linearity check.....	67

INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROMAGNETIC COMPATIBILITY (EMC) –**Part 4-3: Testing and measurement techniques –
Radiated, radio-frequency electromagnetic field immunity test****FOREWORD**

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International Standard IEC 61000-4-3 has been prepared by subcommittee 77B: High frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

It forms part 4-3 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107.

This fourth edition cancels and replaces the third edition published in 2006, Amendment 1:2007 and Amendment 2:2010. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) testing using multiple test signals has been described;
- b) additional information on EUT and cable layout has been added;
- c) the upper frequency limitation has been removed to take account of new services;
- d) the characterization of the field as well as the checking of power amplifier linearity of the immunity chain are specified.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
77B/830/FDIS	77B/825/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61000 series, published under the general title *Electromagnetic compatibility (EMC)*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

Part 1: General

General considerations (introduction, fundamental principles)

Definitions, terminology

Part 2: Environment

Description of the environment

Classification of the environment

Compatibility levels

Part 3: Limits

Emission limits

Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

Measurement techniques

Testing techniques

Part 5: Installation and mitigation guidelines

Installation guidelines

Mitigation methods and devices

Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: IEC 61000-6-1).

This part is an international standard which gives immunity requirements and test procedures related to radiated, radio-frequency, electromagnetic fields.

ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-3: Testing and measurement techniques – Radiated, radio-frequency electromagnetic field immunity test

1 Scope

This part of IEC 61000 is applicable to the immunity requirements of electrical and electronic equipment to radiated electromagnetic energy. It establishes test levels and the required test procedures.

The object of this document is to establish a common reference for evaluating the immunity of electrical and electronic equipment when subjected to radiated, radio-frequency electromagnetic fields. The test method documented in this part of IEC 61000 describes a consistent method to assess the immunity of an equipment or system against RF electromagnetic fields from RF sources not in close proximity to the EUT. The test environment is specified in Clause 6.

NOTE 1 As described in IEC Guide 107, this is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and if applied, they are responsible for determining the appropriate test levels and performance criteria. TC 77 and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular immunity tests for their products.

NOTE 2 Immunity testing against RF sources in close proximity to the EUT is defined in IEC 61000-4-39.

Particular considerations are devoted to the protection against radio-frequency emissions from digital radiotelephones and other RF emitting devices.

NOTE 3 Test methods are defined in this part for evaluating the effect that electromagnetic radiation has on the equipment concerned. The simulation and measurement of electromagnetic radiation is not adequately exact for quantitative determination of effects. The test methods defined in this basic document have the primary objective of establishing an adequate reproducibility of testing configuration and repeatability of test results at various test facilities.

This document is an independent test method. It is not possible to use other test methods as substitutes for claiming compliance with this document.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161, *International Electrotechnical Vocabulary (IEV) – Part 161: Electromagnetic compatibility* (available at www.electropedia.org)